

Notice of References Cited	Application/Control No. 09/620,021	Applicant(s)/Patent Under Reexamination RAJSKI ET AL.	
	Examiner Phung M. Chung	Art Unit 2133	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Rajski et al "Test Data Decompression for Multiple Scan Designs with Boundary Scan" IEEE transactions on computer, vol. 47 NO. 11, November 1998.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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